

**Search Notes**

Application/Control No.

10/775,474

Examiner

David E. Bochna

Applicant(s)/Patent under  
Reexamination

KATAYAMA ET AL.

Art Unit

3679

**SEARCHED**

Class	Subclass	Date	Examiner
285	242	1/5/2006	DB
	244		
	250		
	252		
	254		
	256		
	222.3		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR